

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 241098US2SRD		SERIAL NO. <u>10/631/192</u> <u>NEW APPLICATION</u>	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Mizuki ONO, et al.			
				FILING DATE HEREWITH		GROUP <u>2815</u>	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<u>EO</u>	AO	2002-16063	01/18/02	Japan	<u>—</u>	x	
<u>EO</u>	AP	2000-307010	11/02/02	Japan	<u>—</u>	x	
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<u>EO</u>	AW	G. LUCOVSKY, et al., "Microscopic Model for Enhanced Dielectric Constants in Low Concentration SiO ₂ -Rich Noncrystalline Zr and Hf Silicate Alloys", APPLIED PHYSICS LETTERS, Vol. 77, No. 18, October 30, 2000, pgs. 2912-2914					
<u>EO</u>	AX	Angus I. KINGON, et al., "Alternative Dielectrics to Silicon Dioxide for Memory and Logic Devices", NATURE, Vol. 406, August 31, 2000, pgs. 1032-1038					
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <u>EO</u>				Date Considered <u>6-25-04</u>			

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.